



IPW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Yuko INATOMI et al.

Group Art Unit: 2859

Application No.: 10/608,496

Examiner: G. VERBITSKY

Filed: June 30, 2003

Docket No.: 116391

For: METHOD FOR MEASURING DIFFUSION COEFFICIENT IN CONDUCTIVE MELTS,
AND APPARATUS FOR MEASURING THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection, Notice of Allowance or other action that closes prosecution (e.g., Quayle Action).
- ☒ a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).
- ☒ 2. Each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart application, and this communication was not received by any individual designated in §1.56(c) more than thirty days prior to the filing of this Information Disclosure Statement.

- ☒ 3. The reference was cited in a counterpart foreign application. An English language version of the EPO communication is attached for the Examiner's information.

Respectfully submitted,



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PATENT & TRADEMARK OFFICEATTY DOCKET NO.
116391APPLICATION NO.
10/608,496

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Yuko INATOMI et al.FILING DATE
June 30, 2003GROUP
2859

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	1	Takuma Miyake et al., "Measurement of Diffusion Coefficient in Liquid Metal under Static Magnetic Field," Jpn. J. Appl. Phys., vol. 41, pp. L811-L813, Part 2, No. 7A, July 1, 2002

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: June 24, 2005